

Technical Specifications Sheet

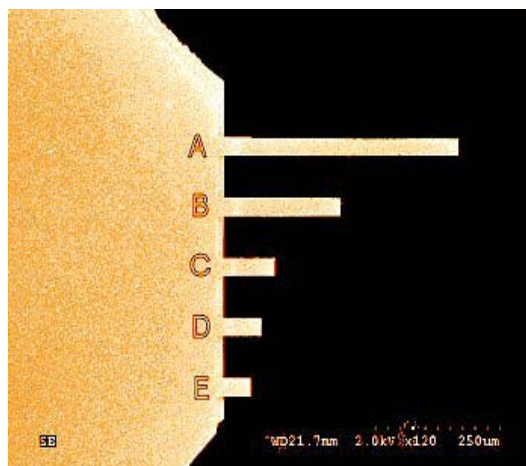
Probe Model: FCLA

APPNANO probes are compatible with most commercially available SPMs. These probes are nanofabricated using highly doped single crystal silicon with unparalleled reproducibility, robustness and sharpness for consistent high resolution imaging capabilities.

The **FCLA Probe** is a tipless force calibration probe with five cantilevers. These probes are designed for the spring constant calibration of SPM probes. This probe has aluminum coating on the reflex side to increase laser signal quality.

Handle Chip Specifications	
L x W x T	3.4 mm x 1.6 mm x 300 μm
Alignment Grooves	YES

Cantilever Specifications	
Material	Si
Shape	Rectangular
Thickness	2.0 μm
Width	32 μm
No. of Cantilevers	5
Reflex Side Coating	Al, 30 nm ± 5



Cantilever	Frequency (kHz)			Spring Constant (N/m)			Length (μm)		
	Typ.	Min	Max	Typ.	Min	Max	Typ.	Min	Max
A	14	13	16	0.12	0.08	0.18	442	440	445
B	60	52	66	0.98	0.70	1.50	218	216	220
C	300	260	350	12	8	18	96	94	98
D	550	470	650	30	20	45	71	69	73
E	1000	860	1200	77	49	118	52	50	54

Ordering Information	
Part Number	Probes
FCL-5	5
FCL-10	10
Larger Quantities are available upon request.	

NOTES :

1. The specification range is **guaranteed**. The values of spring constant and frequency are calculated using mathematical formulation.
2. These probes feature **alignment grooves** compatible with all alignment chips available in the market.
3. Please contact our **distributor** in your area to **order** the probes.
4. For more technical information, please contact either our distributor in your area or e-mail us directly at info@appnano.com.



www.appnano.com

Applied NanoStructures, Inc.
1700 Wyatt Dr. Suite 12, Santa Clara, CA 95054, USA

Tel: 1 408 567 0115 Fax : 1 408 516 4917

E-mail : info@appnano.com